

**Pinout Table**

Pin #	Pin Name	Type	Description
1, 2	Q0 nQ0	Output	LVPECL output clock
3, 4	Q1 nQ1	Output	LVPECL output clock
5, 6	Q2 nQ2	Output	LVPECL output clock
7, 8	Q3 nQ3	Output	LVPECL output clock
9, 10	Q4 nQ4	Output	LVPECL output clock
11	V <sub>EE</sub>	Power	Negative power supply
12	CLK_SEL	Input	Clock input source selection pin
13, 14	CLK0 nCLK0	Input	Differential clock input. LVPECL, LVECL, LVDS, CML, HSTL, HCSL
15	NC	-	No Connect
16, 17	CLK1 nCLK1	Input	Differential clock input. LVPECL, LVECL, LVDS, CML, HSTL, HCSL
18, 20	V <sub>DD</sub>	Power	Power supply
19	nEN	Input	Synchronizing clock enable. When LOW, clock outputs enabled. When HIGH, Q outputs are forced low, nQ outputs forced high.

## Function Table

Table 1: Input select function

CLK_SEL	Function
0	CLK0, nCLK0
1	CLK1, nCLK1

Table 2: Output Mode select function

nEN	Outputs	
	Q0:Q4	nQ0:nQ4
1	Disabled; LOW	Disabled; HIGH
0	Enabled	Enabled

Table 3: Input select function

Input		Output		Device Mode
CLK0 / CLK1	nCLK0 / nCLK1	Q0:Q4	nQ0:nQ4	
LOW	HIGH	LOW	HIGH	Diff. -> Diff., Non-Inverting
HIGH	LOW	HIGH	LOW	Diff. -> Diff., Non-Inverting
LOW	Biased, Figure 1	LOW	HIGH	S-E -> Diff., Non-Inverting
HIGH	Biased, Figure 1	HIGH	LOW	S-E -> Diff., Non-Inverting
Biased, Figure 1	LOW	HIGH	LOW	S-E -> Diff., Inverting
Biased, Figure 1	HIGH	LOW	HIGH	S-E -> Diff., Inverting

**Maximum Ratings** (Above which the useful life may be impaired. For user guidelines, not tested)

Storage temperature.....-55 to +150°C  
 Supply Voltage  $V_{DD}$  (Referenced to  $V_{EE}$ )..... -0.5 to +4.6V  
 Inputs (Referenced to  $V_{EE}$ )..... -0.5 to  $V_{DD}+0.5V$   
 Clock Output (Referenced to  $V_{EE}$ )..... -0.5 to  $V_{DD}+0.5V$

**Note:**

Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

**Power Supply Characteristics and Operating Conditions**

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
$V_{DD}$	Supply Voltage		3.0	3.3	3.6	V
			2.375	2.5	2.625	
$V_{EE}$	Negative supply voltage		-0.5			
$I_{DD}$	Power Supply Current	Outputs unloaded			120	mA
$T_A$	Ambient Operating Temperature		-40		85	°C

**DC Electrical Specifications - Differential Inputs**

Symbol	Parameter		Min.	Typ.	Max.	Units
$I_{IH}$	Input High current: CLK0, CLK1	Input = $V_{DD}$			150	uA
	Input High current: nCLK0, nCLK1	Input = $V_{DD}$			150	uA
$I_{IL}$	Input Low current: CLK0, CLK1	Input = GND	-5			uA
	Input Low current: nCLK0, nCLK1	Input = GND	-150			uA
$C_{IN}$	Input capacitance			4		PF
$V_{IH}$	Input high voltage				$V_{DD}+0.3$	V
$V_{IL}$	Input low voltage		-0.3			V
$V_{ID}$	Input Differential Amplitude PK-PK		0.15		$V_{DD}-0.85$	V
$V_{CM}$	Common mode input voltage		$V_{EE}+0.5$		$V_{DD}-0.85$	V

### DC Electrical Specifications - LVCMOS Inputs

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Units
$I_{IH}$	Input High current	Input = $V_{DD}$			150	$\mu A$
$I_{IL}$	Input Low current	Input = GND	-150			$\mu A$
$V_{IH}$	Input high voltage	$V_{DD}=3.3V$	2.0		3.765	V
$V_{IL}$	Input low voltage	$V_{DD}=3.3V$	-0.3		0.8	V
$V_{IH}$	Input high voltage	$V_{DD}=2.5V$	1.7		$V_{DD}+0.3$	V
$V_{IL}$	Input low voltage	$V_{DD}=2.5V$	-0.3		0.7	V

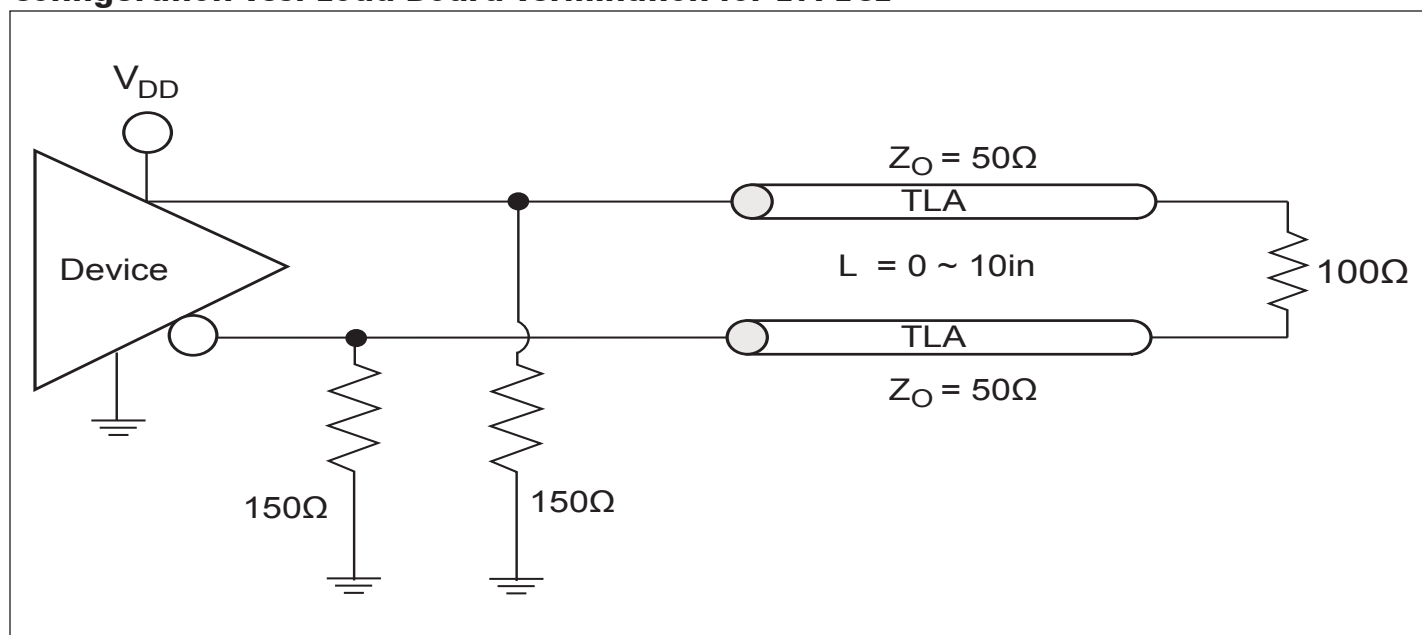
### DC Electrical Specifications- LVPECL Outputs

Parameter	Description	Conditions	Min.	Typ.	Max.	Units
$V_{OH}$	Output High voltage	$V_{DD}=3.3V$	2.1		2.6	V
		$V_{DD}=2.5V$	1.3		1.6	
$V_{OL}$	Output Low voltage	$V_{DD}=3.3V$	1.3		1.8	V
		$V_{DD}=2.5V$	0.5		1.0	

## AC Electrical Specifications

Parameter	Description	Conditions	Min.	Typ.	Max.	Units
F <sub>OUT</sub>	Clock output frequency	LVPECL			1500	MHz
T <sub>r</sub>	Output rise time	From 20% to 80%		150		ps
T <sub>f</sub>	Output fall time	From 80% to 20%		150		ps
T <sub>ODC</sub>	Output duty cycle	Frequency<650MHz, LVPECL input used	48		52	%
V <sub>PP</sub>	Output swing Single-ended	Frequency<650MHz	400			mV
T <sub>j</sub>	Buffer additive jitter RMS	Differential clock input		0.03		ps
T <sub>SK</sub>	Output Skew				70	ps
T <sub>PD</sub>	Propagation Delay			1200		ps
T <sub>P2P Skew</sub>	Part to Part Skew				150	ps

## Configuration Test Load Board Termination for LVPECL



## Application information

### Suggest for Unused Inputs and Outputs

#### LVC MOS Input Control Pins

It is suggested to add pull-up=4.7k and pull-down=1k for LVC-MOS pins even though they have internal pull-up/down but with much higher value ( $\geq 50k$ ) for higher reliability design.

#### Differential +IN/-IN Input Pins

They can be left floating if not used. Connect them 1k to GND is optional for the additional protection.

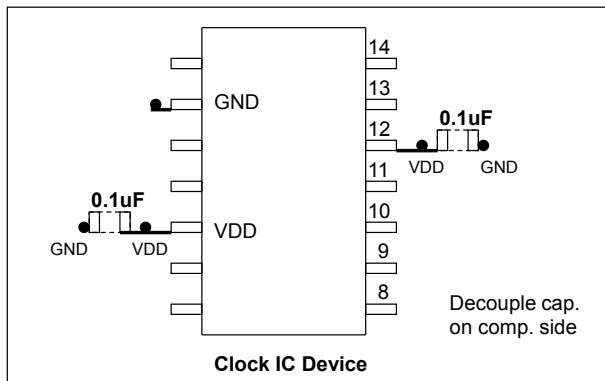
#### Outputs

All unused outputs are suggested to be left open and not connected to any trace. This can lower the IC power supply power.

## Power Decoupling & Routing

#### VDD Pin Decoupling

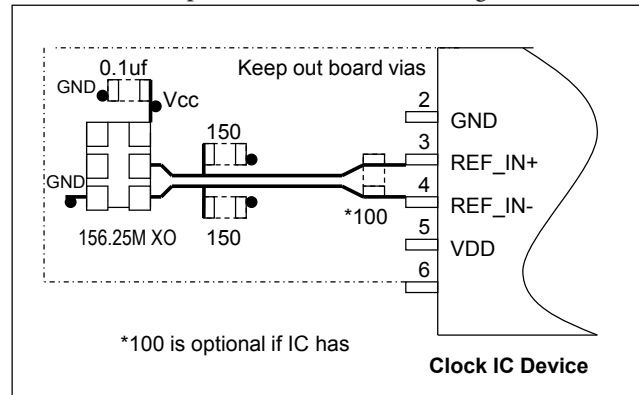
As general design rule, each VDD pin must have a 0.1uF decoupling capacitor. For better decoupling, 1uF can be used. Locating the decoupling capacitor on the component side has better decoupling filter result as shown below.



Placement of Decoupling caps

#### Differential Clock Trace Routing

Always route differential signals symmetrically, make sure there is enough keep-out space to the adjacent trace ( $>20\text{mil.}$ ). In 156.25MHz XO drives IC example, it is better routing differential trace on component side as the following.



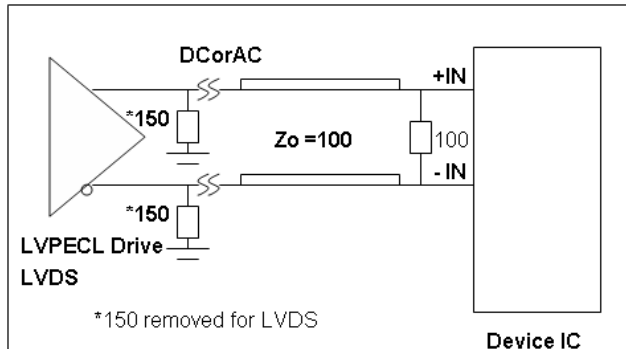
IC routing for XO drive

Clock timing is the most important component in PCB design, so its trace routing must be planned and routed as a first priority in manual routing. Some good practices are to use minimum vias (total trace vias count  $<4$ ), use independent layers with good reference plane and keep other signal traces away from clock traces ( $>20\text{mil.}$ ) etc.

## LVPECL and LVDS Input Interface

### LVPECL and LVDS DC/ AC Input

LVPECL and LVDS clock input to this IC is connected as shown below.

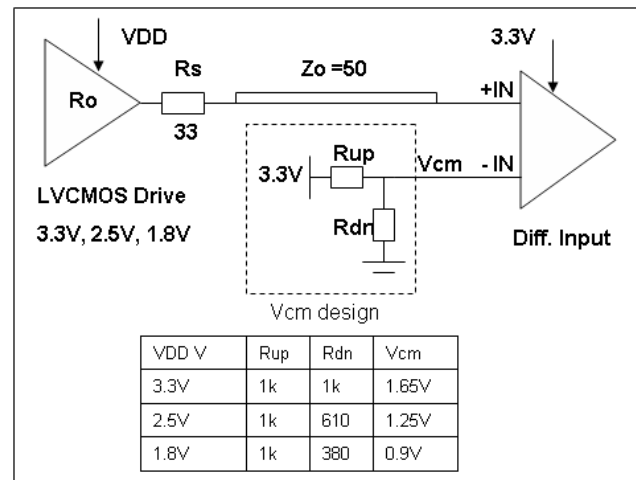


LVPECL/ LVDS Input

## CMOS Clock DC Drive Input

LVC MOS clock has voltage  $V_{oh}$  levels such as 3.3V, 2.5V, 1.8V.

CMOS drive requires a  $V_{cm}$  design at the input:  $V_{cm} = \frac{1}{2}$  (CMOS V) as shown below 7.  $R_s = 22 \sim 33\Omega$  typically.

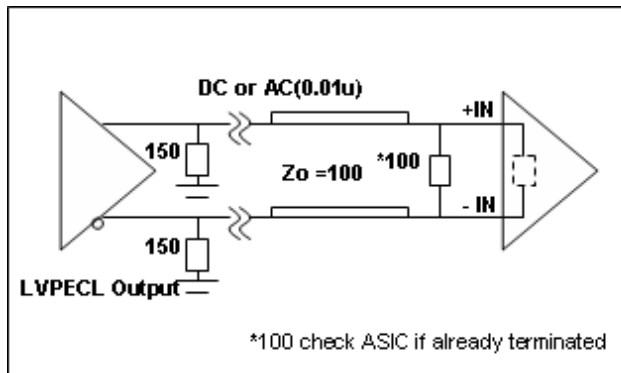


CMOS DC Input  $V_{cm}$  Design

## Device LVPECL Output Terminations

### LVPECL Output Popular Termination

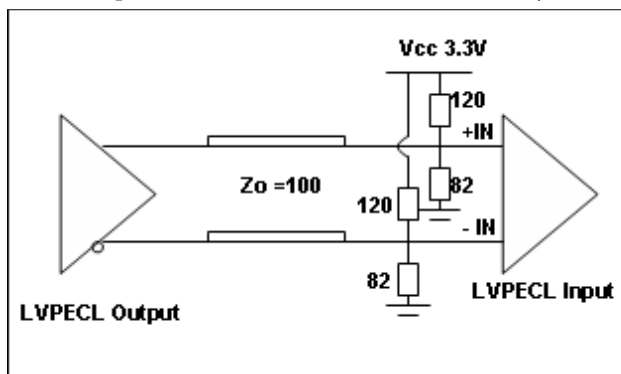
The most popular LVPECL termination is 150ohm pull-down bias and 100ohm across at RX side. Please consult ASIC data-sheet if it already has 100ohm or equivalent internal termination. If so, do not connect external 100ohm across as shown in below. This popular termination's advantage is that it does not allow any bias through from Vcc. This prevents Vcc system noise coupling onto clock trace.



LVPECL Output Popular Termination

### LVPECL Output Thevenin Termination

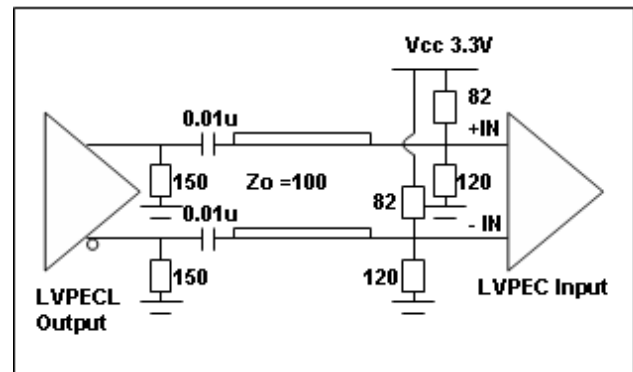
Figure below shows LVPECL output Thevenin termination which is used for shorter trace drive (<5in.), but it takes Vcc bias current and Vcc noise can get onto clock trace. It also requires more component count. So it is seldom used today.



LVPECL Thevenin Output Termination

### LVPECL Output AC Thevenin Termination

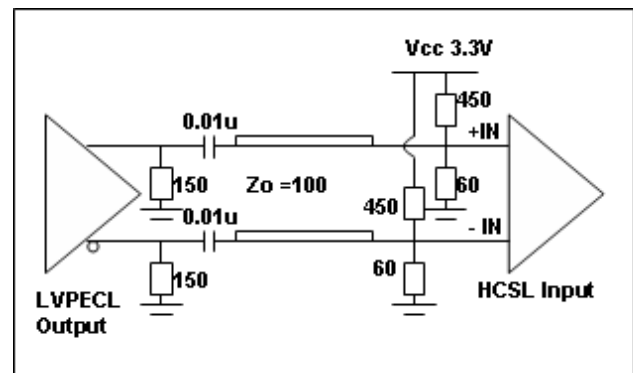
LVPECL AC Thevenin terminations require a 150ohm pull-down before the AC coupling capacitor at the source as shown below. Note that pull-up/down resistor value is swapped compared to previous figure. This circuit is good for short trace (<5in.) application only.



LVPECL Output AC Thevenin Termination

### LVPECL Output Drive HCSL Input

Using the LVPECL output to drive a HCSL input can be done using a typical LVPECL AC Thevenin termination scheme. Use pull-up/down 450/60ohm to generate Vcm=0.4V for the HCSL input clock. This termination is equivalent to 50Ohm load as shown.

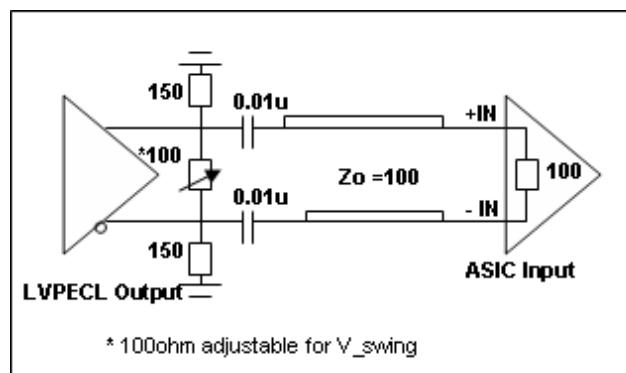


LVPECL Output Drive HCSL Termination



### LVPECL Output V<sub>swing</sub> Adjustment

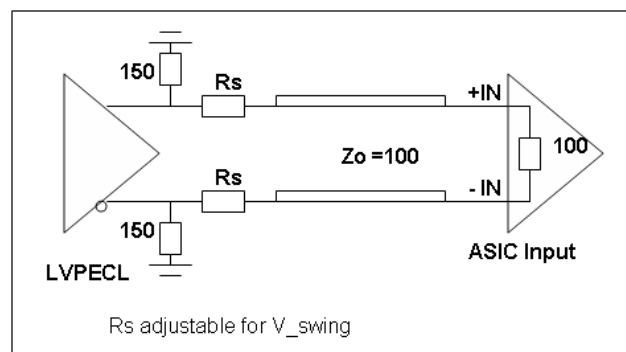
It is suggested to add another cross 100ohm at TX side to tune the LVPECL output V<sub>swing</sub> without changing the optimal 150ohm pull-down bias. This form of double termination can reduce the V<sub>swing</sub> in ½ of the original at the RX side. By fine tuning the 100ohm resistor at the TX side with larger values like 150 to 200ohm, one can increase the V<sub>swing</sub> by > 1/2 ratio.



LVPECL Output V<sub>swing</sub> Adjustment

### LVPECL V<sub>swing</sub> Adjustment using Rs

Another way to control V<sub>swing</sub> is by adding serial Rs. Rs value is tunable between 22 to 33 ohm depending on application. This method may reduce the clock drive PCB trace in slower Tr/Tf.



LVPECL V<sub>swing</sub> Adjustment using Rs

### Clock Jitter Definitions

$$\text{Total jitter} = \text{RJ} + \text{DJ}$$

Random Jitter (RJ) is unpredictable and unbounded timing noise that can fit in a Gaussian math distribution in RMS. RJ test values are directly related with how long or how many test samples are available. Deterministic Jitter (DJ) is timing jitter that is predictable and periodic in fixed interference frequency. Total Jitter (TJ) is the combination of random jitter and deterministic jitter: , where is a factor based on total test sample count. JEDEC std. specifies digital clock TJ in 10k random samples.

### Phase Jitter

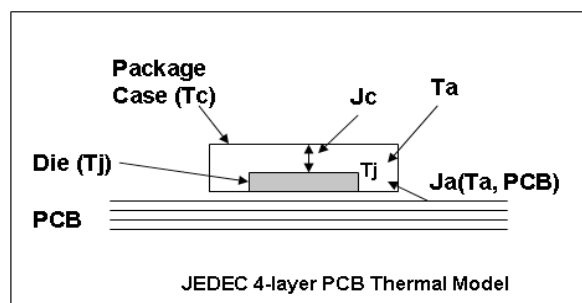
Phase noise is short-term random noise attached on the clock carrier and it is a function of the clock offset from the carrier, for example dBc/Hz@10kHz which is phase noise power in 1-Hz normalized bandwidth vs. the carrier power @10kHz offset. Integration of phase noise in plot over a given frequency band yields RMS phase jitter, for example, to specify phase jitter <=1ps at 12k to 20MHz offset band as SONET standard specification.

### PCIe Ref\_CLK Jitter

PCIe reference clock jitter specification requires testing via the PCI-SIG jitter tool, which is regulated by US PCI-SIG organization. The jitter tool has PCIe Serdes embedded filter to calculate the equivalent jitter that relates to data link eye closure. Direct peak-peak jitter or phase jitter test data, normally is higher than jitter measure using PCI-SIG jitter tool. It has high-frequency jitter and low-frequency jitter spec. limit. For more information, please refer to the PCI-SIG website: <http://www.pcisig.com/specifications/pcieexpress/>

### Device Thermal Calculation

Figure below shows the JEDEC thermal model in a 4-layer PCB.



JEDEC IC Thermal Model

Important factors to influence device operating temperature are:

- 1) The power dissipation from the chip (P<sub>chip</sub>) is after subtracting power dissipation from external loads. Generally it can be the no-load device I<sub>dd</sub>
- 2) Package type and PCB stack-up structure, for example, 1oz 4 layer board. PCB with more layers and are thicker has better heat dissipation

3) Chassis air flow and cooling mechanism. More air flow M/s and adding heat sink on device can reduce device final die junction temperature Tj

The individual device thermal calculation formula:

$$T_j = T_a + P_{chip} \times J_a$$

$$T_c = T_j - P_{chip} \times J_c$$

J<sub>a</sub> \_\_\_ Package thermal resistance from die to the ambient air in C/W unit; This data is provided in JEDEC model simulation. An air flow of 1m/s will reduce J<sub>a</sub> (still air) by 20~30%

J<sub>c</sub> \_\_\_ Package thermal resistance from die to the package case in C/W unit

T<sub>j</sub> \_\_\_ Die junction temperature in C (industry limit <125C max.)

T<sub>a</sub> \_\_\_ Ambient air temperature in C

T<sub>c</sub> \_\_\_ Package case temperature in C

P<sub>chip</sub>\_\_\_ IC actually consumes power through I<sub>ee</sub>/GND current

### Thermal calculation example

To calculate T<sub>j</sub> and T<sub>c</sub> of PI6CV304 in an SOIC-8 package:

Step 1: Go to Pericom web to find J<sub>a</sub>=157 C/W, J<sub>c</sub>=42 C/W

<http://www.pericom.com/support/packaging/packaging-mechanicals-and-thermal-characteristics/>

Step 2: Go to device datasheet to find I<sub>dd</sub>=40mA max.

I <sub>DD</sub>	Supply Current	C <sub>L</sub> = 33pF/33MHz	20	mA
		C <sub>L</sub> = 33pF/60MHz	40	
		C <sub>L</sub> = 22pF/80MHz	35	
		C <sub>L</sub> = 15pF/100MHz	32	
		C <sub>L</sub> = 10pF/125MHz	28	
		C <sub>L</sub> = 10pF/155MHz	41	

Step 3: P<sub>total</sub> = 3.3Vx40mA=0.132W

Step 4: If T<sub>a</sub>=85C

$$T_j = 85 + J_a \times P_{total} = 85 + 25.9 = 105.7C$$

$$T_c = T_j + J_c \times P_{total} = 105.7 - 5.54 = 100.1C$$

Note:

The above calculation is directly using I<sub>dd</sub> current without subtracting the load power, so it is a conservative estimation. For more precise thermal calculation, use P<sub>unload</sub> or P<sub>chip</sub> from device I<sub>ee</sub> or GND current to calculate T<sub>j</sub>, especially for LVPECL buffer ICs that have a 150ohm pull-down and equivalent 100ohm differential RX load.

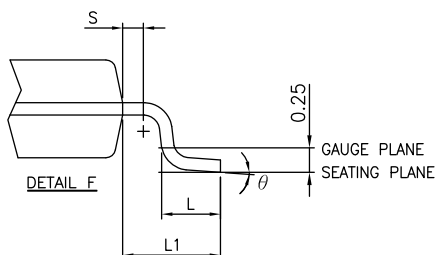
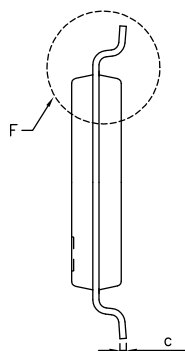
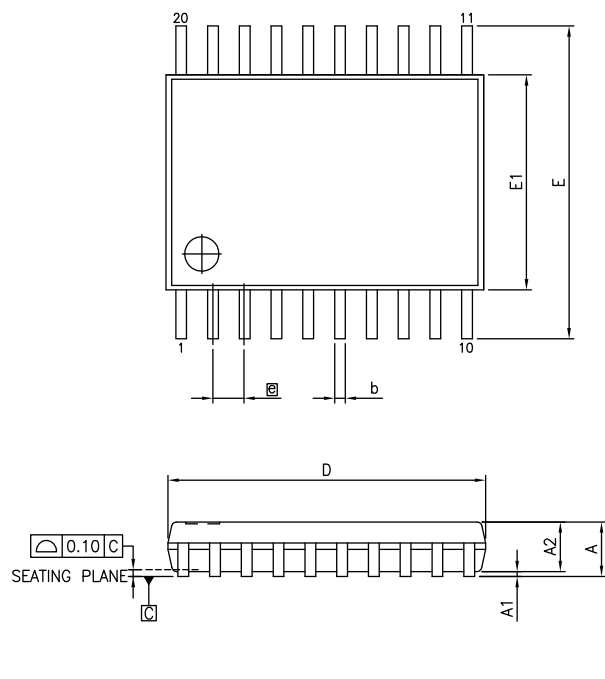
## Thermal Information

Symbol	Description	Condition	
Θ <sub>JA</sub>	Junction-to-ambient thermal resistance	Still air	84.0 °C/W
Θ <sub>JC</sub>	Junction-to-case thermal resistance		17.0 °C/W

## Packaging Mechanical: 20-Pin TSSOP (L)

VARIATIONS (ALL DIMENSIONS SHOWN IN MM)

SYMBOLS	MIN.	NOM.	MAX.
A	—	—	1.20
A1	0.05	—	0.15
A2	0.80	—	1.05
b	0.19	—	0.30
C	0.09	—	0.20
D	6.40	6.50	6.60
E1	4.30	4.40	4.50
E	6.40 BSC		
e	0.65 BSC		
L1	1.00 REF		
L	0.45	0.60	0.75
S	0.20	—	—
$\theta$	0°	—	8°



- Notes:**
- Refer JEDEC MO-153F/AC
  - Controlling dimensions in millimeters
  - Package outline exclusive of mold flash and metal burr



DATE: 05/03/12

DESCRIPTION: 20-pin, 173mil Wide TSSOP

PACKAGE CODE: L

DOCUMENT CONTROL #: PD-1311

REVISION: F

## Ordering Information<sup>(1-3)</sup>

Ordering Code	Package Code	Package Description
PI6C4911505-07LIE	L	20-pin, TSSOP, Pb-Free and Green
PI6C4911505-07LIE X	L	20-pin, TSSOP, Pb-Free and Green, Tape & Reel

### Notes:

1. Thermal characteristics can be found on the company web site at [www.pericom.com/packaging/](http://www.pericom.com/packaging/)
2. E = Pb-free and Green
3. Adding an X suffix = Tape/Reel